# 2SD1119

## Silicon NPN epitaxial planar type

## For low-frequency power amplification

## ■ Features

- Low collector-emitter saturation voltage V<sub>CE(sat)</sub>
- Satisfactory operation performances at high efficiency with the low-voltage power supply.
- Mini power type package, allowing downsizing of the equipment and automatic insertion through the tape packing and the magazine packing.

## ■ Absolute Maximum Ratings $T_a = 25$ °C

Parameter	Symbol	Rating	Unit	
Collector-base voltage (Emitter open)	$V_{CBO}$	40	V	
Collector-emitter voltage (Base open)	V <sub>CEO</sub>	25	V	
Emitter-base voltage (Collector open)	$V_{EBO}$	7	V	
Collector current	$I_{C}$	3	A	
Peak collector current	I <sub>CP</sub>	5	A	
Collector power dissipation *	P <sub>C</sub>	1	W	
Junction temperature	$T_{j}$	150	°C	
Storage temperature	$T_{stg}$	-55 to +150	S°C	

Note) \*: Printed circuit board: Copper foil area of 1 cm<sup>2</sup> or more, and the board thickness of 1.7 mm for the collector portion

# Unit: mm 4.5±0.1 1.6±0.2 1.5±0.1 1.

Marking Symbol: T

## ■ Electrical Characteristics $T_a = 25$ °C $\pm 3$ °C

Parameter	Symbol	Conditions	Min	Тур	Max	Unit
Collector-emitter voltage (Base open)	$V_{CEO}$	$I_C = 1 \text{ mA}, I_B = 0$	25			V
Emitter-base voltage (Collector open)	$V_{EBO}$	$I_E = 10 \mu\text{A}, I_C = 0$	7			V
Collector-base cutoff current (Emitter open)	$I_{CBO}$	$V_{CB} = 10 \text{ V}, I_{E} = 0$			0.1	μΑ
Forward current transfer ratio *1	h <sub>FE1</sub> *2	$V_{CE} = 2 \text{ V}, I_{C} = 0.5 \text{ A}$	230		600	_
	h <sub>FE2</sub>	$V_{CE} = 2 \text{ V}, I_{C} = 2 \text{ A}$	150			
Collector-emitter saturation voltage *1	V <sub>CE(sat)</sub>	$I_C = 3 A, I_B = 0.1 A$			1	V
Transition frequency	$f_T$	$V_{CB} = 6 \text{ V}, I_E = -50 \text{ mA}, f = 200 \text{ MHz}$		150		MHz
Collector output capacitance	C <sub>ob</sub>	$V_{CB} = 20 \text{ V}, I_{E} = 0, f = 1 \text{ MHz}$			50	pF
(Common base, input open circuited)						

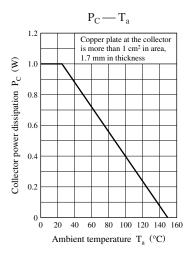
Note) 1. Measuring methods are based on JAPANESE INDUSTRIAL STANDARD JIS C 7030 measuring methods for transistors.

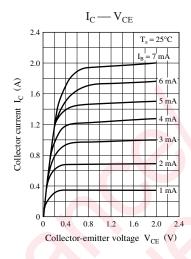
### 2. \*1: Pulse measurement

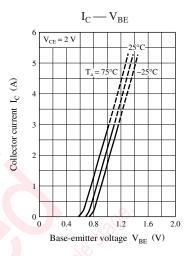
\*2: Rank classification

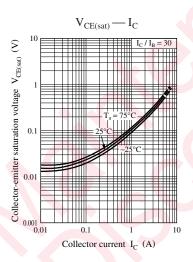
Rank	Q	R
$h_{\rm FE1}$	230 to 380	340 to 600

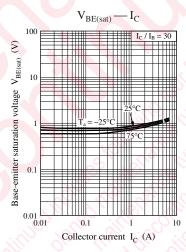
# **Panasonic**

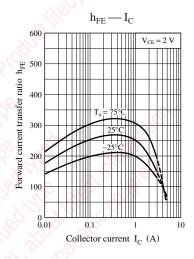


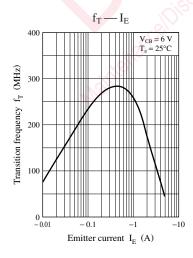


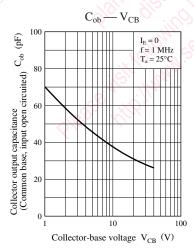












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